

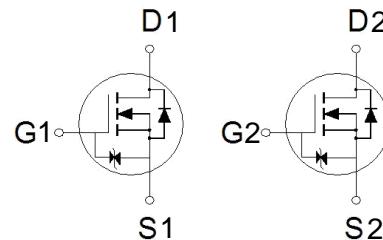
**NIKO-SEM**

**Dual N-Channel Logic Level  
Enhancement Mode Field Effect Transistor**

**PZ5S6JZ**  
**SOT-363**  
**Halogen-Free & Lead-Free**

**PRODUCT SUMMARY**

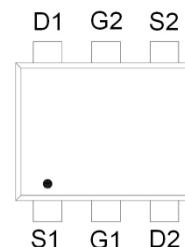
$V_{(BR)DSS}$	$R_{DS(on)}$	$I_D$
30V	480m $\Omega$	0.57A

**Features**

- Pb-Free, Halogen Free and RoHS compliant.
- Low  $R_{DS(on)}$  to Minimize Conduction Losses.
- Ohmic Region Good  $R_{DS(on)}$  Ratio.
- Optimized Gate Charge to Minimize Switching Losses.
- ESD Protection - HBM Class : 2.

**Applications**

- Protection Circuits Applications.
- Logic/Load Switch Circuits Applications.
- Space Limit & Smart Devices Applications.



G: GATE  
D: DRAIN  
S: SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS		UNITS
Gate-Source Voltage	$V_{GS}$	$\pm 12$		V
Continuous Drain Current <sup>1</sup>	$I_D$	0.57		A
$T_A = 70^\circ\text{C}$		0.45		
Pulsed Drain Current <sup>2</sup>	$I_{DM}$	1.6		A
Power Dissipation	$P_D$	0.3		W
$T_A = 70^\circ\text{C}$		0.2		
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150		°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		400	°C / W

<sup>1</sup>Limited by maximum junction temperature.

<sup>2</sup>Limited by package.

**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.4	0.8	1.2	

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Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 10V$			$\pm 30$	$\mu A$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 30V, V_{GS} = 0V$			1	$\mu A$
		$V_{DS} = 30V, V_{GS} = 0V, T_J = 55^\circ C$			10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 0.5A$		323	480	$m\Omega$
		$V_{GS} = 4V, I_D = 0.5A$		335	500	
		$V_{GS} = 2.5V, I_D = 0.25A$		406	700	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5V, I_D = 0.5A$	2			S

DYNAMIC						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		50		$pF$
Output Capacitance	$C_{oss}$			16		
Reverse Transfer Capacitance	$C_{rss}$			8		
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{GS} = 4.5V, V_{DS} = 15V, I_D = 1A$		1		$nC$
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			0.26		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			0.26		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = 15V, I_D \approx 0.5A, V_{GS} = 4.5V, R_{GEN} = 6\Omega$		17		$nS$
Rise Time <sup>2</sup>	$t_r$			32		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			92		
Fall Time <sup>2</sup>	$t_f$			46		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_J = 25^\circ C$ )						
Continuous Current	$I_S$				0.25	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 0.5A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	$t_{rr}$	$I_F = 1A, dI/dt = 100 A/\mu s$		49		$nS$
Reverse Recovery Charge	$Q_{rr}$			36		$nC$

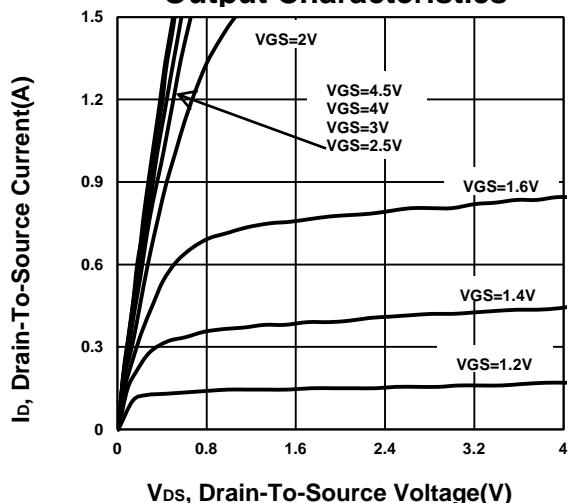
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

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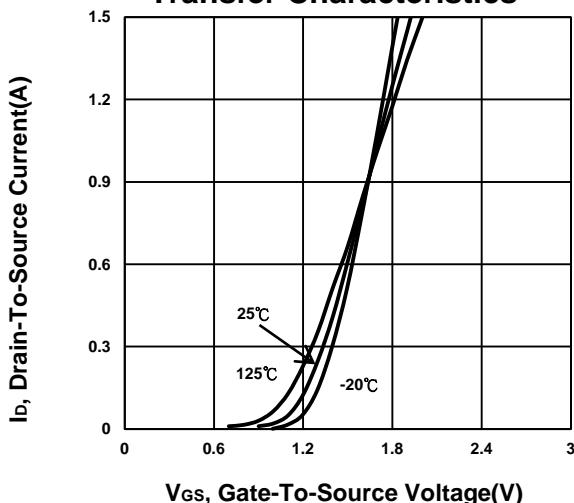
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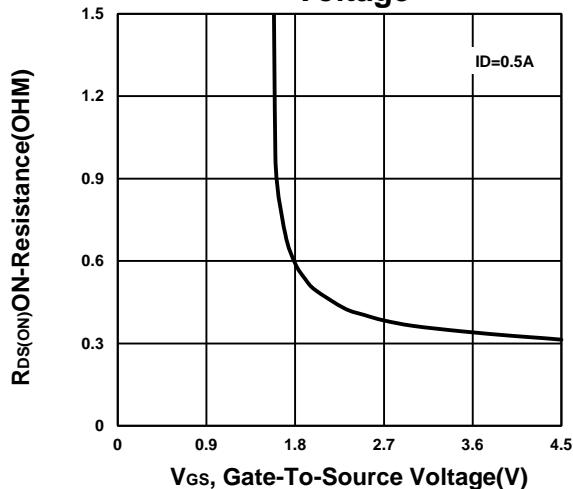
### Output Characteristics



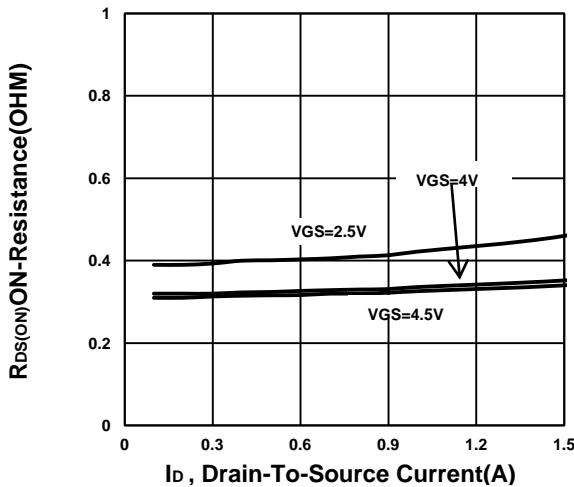
### Transfer Characteristics



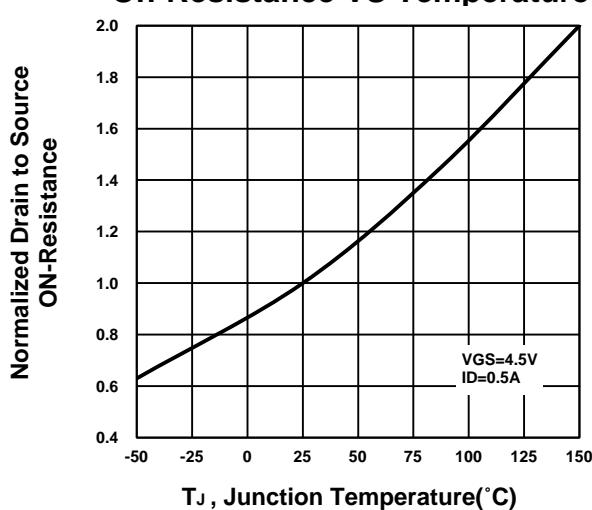
### On-Resistance VS Gate-To-Source Voltage



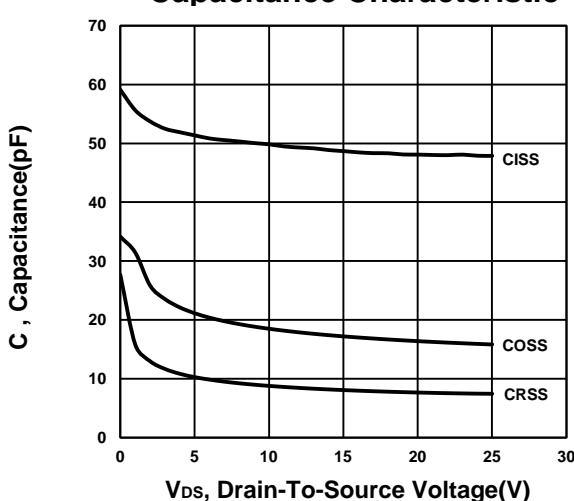
### On-Resistance VS Drain Current



### On-Resistance VS Temperature



### Capacitance Characteristic

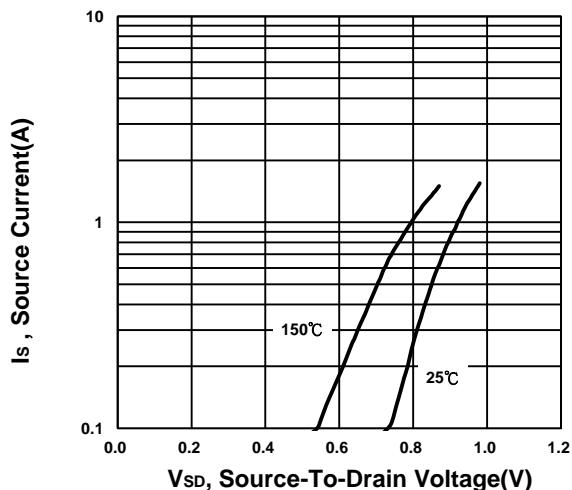


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**Source-Drain Diode Forward Voltage**



**Safe Operating Area**

